



SLOVENSKI STANDARD

oSIST prEN IEC 63287-4:2025

01-julij-2025

Polprevodniški elementi - Smernice za načrtovanje ocenjevanja zanesljivosti - 4. del: Ocena zgodnje odpovedi

Semiconductor devices - Guidelines for reliability qualification plans - Part 4: Early failure assessment

Dispositifs à semiconducteurs - Lignes directrices concernant les plans de qualification de la fiabilité - Partie 4: évaluation des défaillances précoces

Ta slovenski standard je istoveten z: **prEN IEC 63287-4:2025**

<https://standards.iteh.ai/catalog/standards/sist/cf7308c4-2740-4cd1-992b-a0bc41e7496e/osist-pren-iec-63287-4-2025>

ICS:

31.080.01	Polprevodniški elementi (naprave) na splošno	Semiconductor devices in general
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47/2917/CDV

COMMITTEE DRAFT FOR VOTE (CDV)

PROJECT NUMBER: IEC 63287-4 ED1	
DATE OF CIRCULATION: 2025-05-30	CLOSING DATE FOR VOTING: 2025-08-22
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IEC TC 47 : SEMICONDUCTOR DEVICES	
SECRETARIAT: Korea, Republic of	SECRETARY: Mr Cheolung Cha
OF INTEREST TO THE FOLLOWING COMMITTEES:	HORIZONTAL FUNCTION(S):
ASPECTS CONCERNED:	
☒ SUBMITTED FOR CENELEC PARALLEL VOTING Attention IEC-CENELEC parallel voting The attention of IEC National Committees, members of CENELEC, is drawn to the fact that this Committee Draft for Vote (CDV) is submitted for parallel voting. The CENELEC members are invited to vote through the CENELEC online voting system.	☐ NOT SUBMITTED FOR CENELEC PARALLEL VOTING

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TITLE:

Semiconductor devices - Guidelines for reliability qualification plans - Part 4: Early failure assessment

PROPOSED STABILITY DATE: 2030

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